

Enhanced Schottky Contacts using an MIS Structure for Photovoltaic and Other Device Applications

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Background

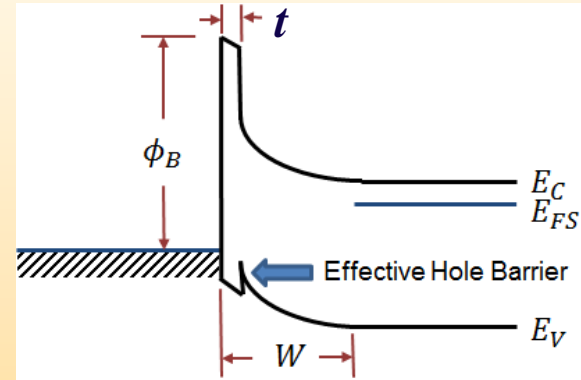
- Majority carrier current (thermionic):

$$J_{0e} = A^* T^2 e^{-q\phi_B/kT} (e^{qV_A/kT} - 1)$$

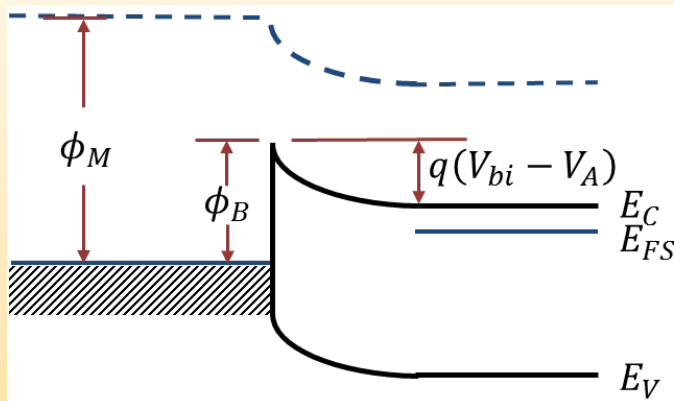
- Minority carrier injection current:

$$J_{0h} = \frac{qD_P n_i^2}{L_P N_D} (e^{qV_A/kT} - 1)$$

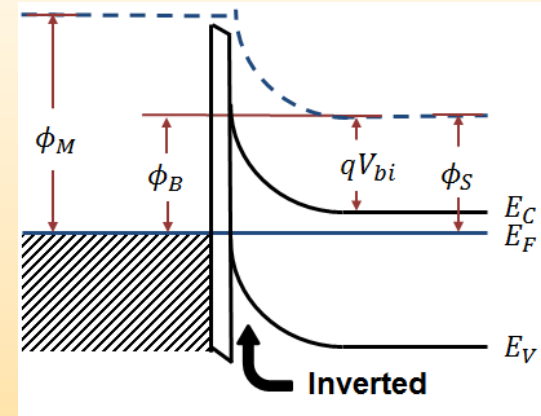
- Majority carrier component is dominant! $J_{0e} \gg J_{0h}$



Heterojunction (Forward Bias)



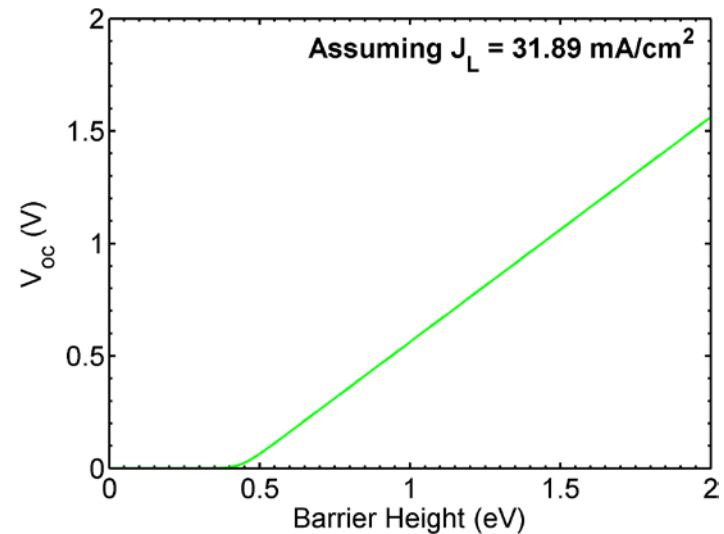
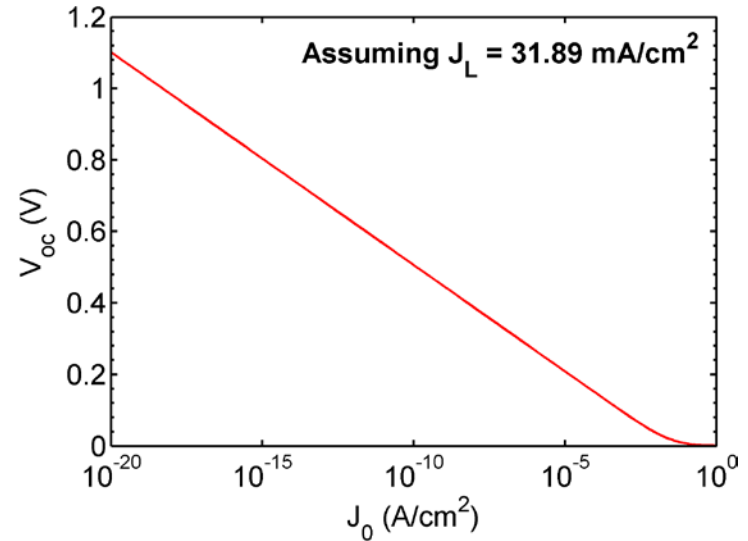
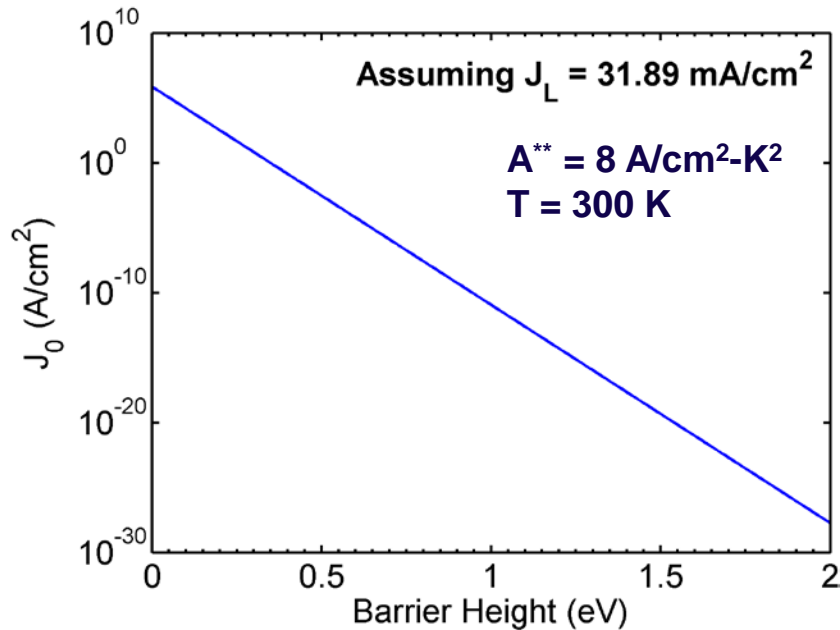
MS Junction (Forward Bias)



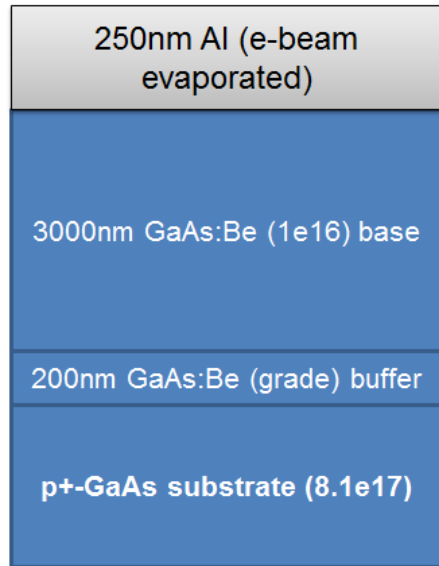
Ideal MIS

Analytical Underpinning

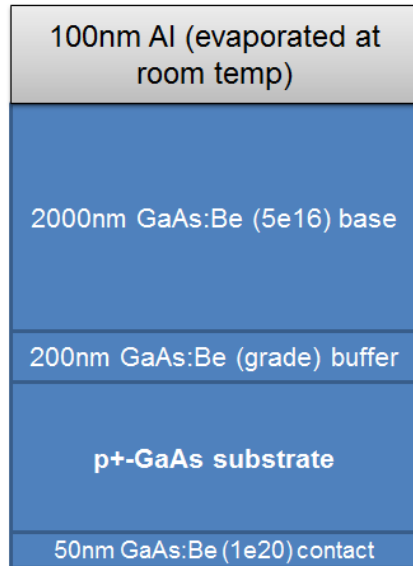
$$V_{oc} = \frac{nkT}{q} \ln\left(\frac{J_L}{J_0} + 1\right)$$



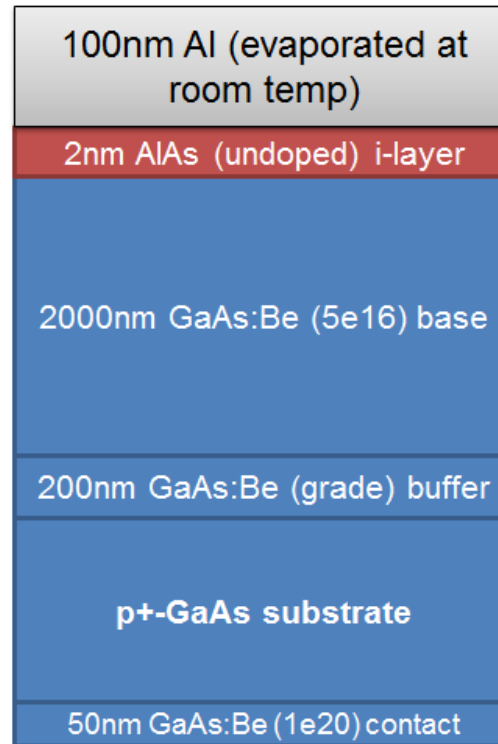
Experimental Approach



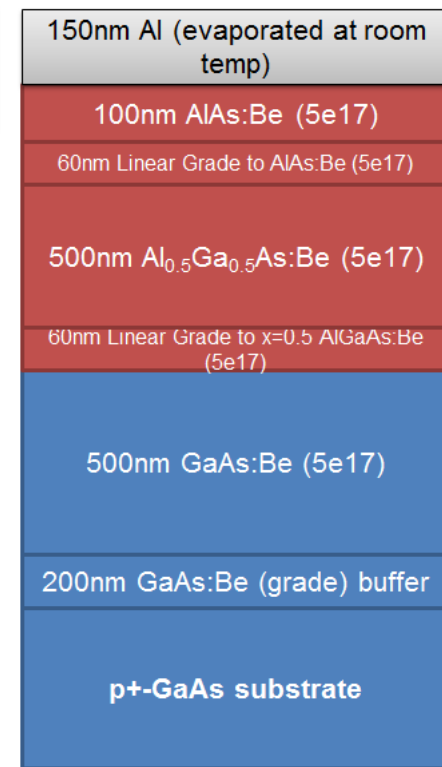
A9-5: Al (E-Beam)



A21-2: Al (MBE)



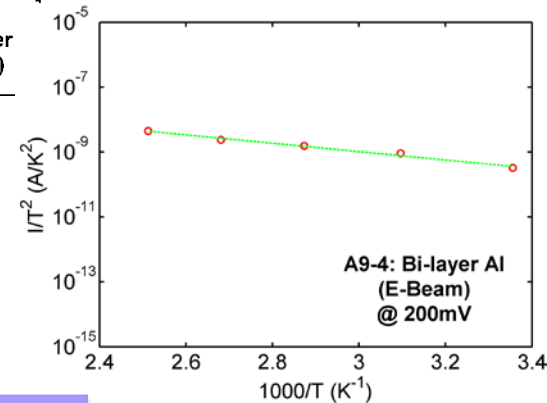
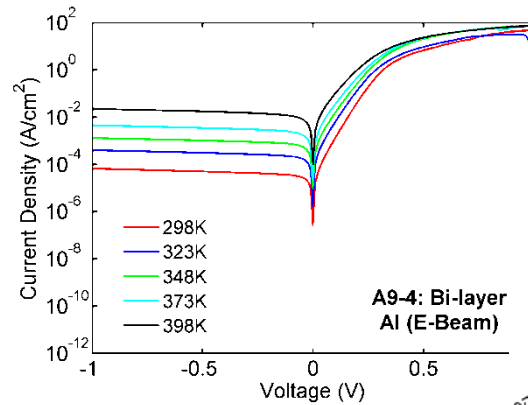
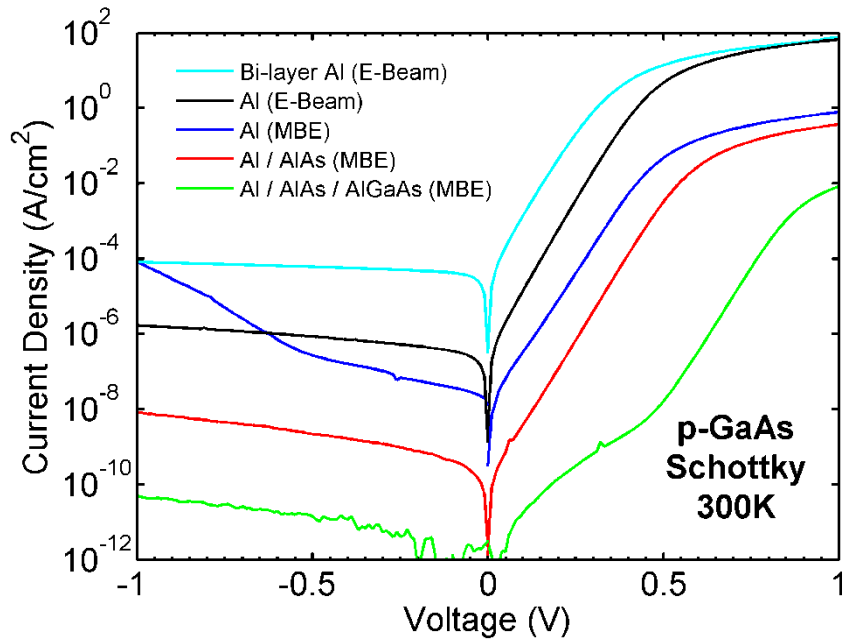
A20-4: Al / AIAs (MBE)



A23-1: Al / AIAs / AlGaAs (MBE)

Baseline

Results - Experimental



Sample ID	n	J_0 (A/cm ²)	Φ_{B-JVT} (meV)
A9-5: Al (E-beam)	1.08	1.03e-6	709
A21-2: Al (MBE)	1.19	2.76e-8	736
A20-4: Al / AIAs (MBE)	1.11	1.97e-10	
A23-1: Al / AIAs / AlGaAs (MBE)	1.14	4.95e-16	933

SBH
+200 meV

Conclusions / Future Work

- Fermi Level Pinning still an inhibitor
- Interested in application to thin-film III-V PV
- Currently working on AZO / ZnO / InP solar cells (7.3% efficient, to be published)

What if a semiconductor alloy existed with...

- Band gap range of 1.42 – 2.67eV
- No miscibility gap
- Lattice-matched to GaAs
- Previously demonstrated in bulk form

Introducing...ZnSe-GaAs!

